


<b>Search Notes</b>  	<b>Application/Control No.</b>  10510289	<b>Applicant(s)/Patent Under Reexamination</b>  KAWAKAMI ET AL.
	<b>Examiner</b>  TAN TRINH	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	3.02, 3.04, 3.06, 425, 22, 76, 77, 87, 575.1, 131, 133, 140, 575.1, 575.8, 150.1, 154.1, 153.1, 175.1	08-02-09	TT
334	1.	08-02-09	TT
315	169.4	08-02-09	TT
348	553, 571, 725, 731, 732, 734, 735, 634, 553, 563	08-02-09	TT
709	204, 239	08-02-2009	TT
EAST	(see print out)	08-02-2009	TT

SEARCH NOTES			
Search Notes		Date	Examiner
EAST		08-02-2009	TT
Checked Double Patent on (US 7,030939) = No DP		08-02-2009	TT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
PG-PUB.	Text search (see print out)	08-02-2009	TT

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